

Notice of References Cited		Application/Control No. 09/937,520	Applicant(s)/Patent Under Reexamination MITANI ET AL.	
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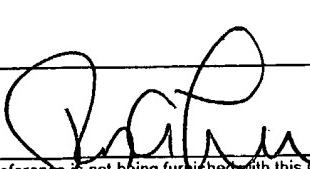
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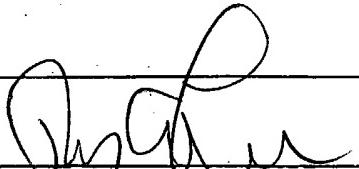
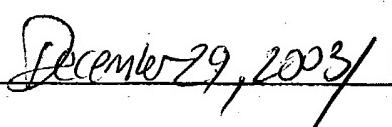
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